



Please amend the specification as follows:

In the Claims:

1. (amended) A nest for holding an integrated circuit during testing, comprising:

(26) a plate having a front side and a back side;
a cavity in the plate for receiving an integrated circuit having a plurality of pins;

a channel through the plate for receiving therethrough an anvil; and
an anvil detachably engaged through the channel, positioned to engage the pins of the integrated circuit and to maintain the pins in alignment,

2. (amended) The nest of Claim 1 wherein the plate comprises a material selected from the group consisting of aluminum, steel, or Torlon®.

6. (amended) A system for testing an integrated circuit comprising:

a test head having at least one contact point;
a handler for placing the integrated circuit in a position for testing;

and

a nest connected to the handler for holding an integrated circuit during testing, comprising:

a plate having a front side and a back side,
a cavity in the plate for receiving an integrated circuit having a plurality of pins;

a channel through the plate for receiving therethrough an anvil; and
an anvil detachably engaged through the channel, positioned to engage the pins of the integrated circuit and to maintain the pins in alignment.

11. (amended) The system of Claim 6 wherein the plate comprises a material selected from the group consisting of aluminum, steel, or Torlon®.

12. (cancelled).

13. (cancelled).

Please add the following new claims:

17. A test apparatus comprising:

a test head having at least one contact point;

a nest adapted to hold an integrated circuit such that at least one lead on said integrated circuit can be touched by said test head contact point when said test head and said nest are juxtaposed during operation of said test apparatus, said nest comprising:

a plate;

a cavity in said plate adapted to receive said integrated circuit;

a channel through said plate adjacent said cavity in a location adjacent said test head contact point when said test head and said nest are juxtaposed; and

an anvil releasably disposed in said channel to provide force sufficient to press said lead on said integrated circuit against said test head contact point during juxtaposition of said test head and said nest.

18. The test apparatus of Claim 17 wherein said plate has front and back surfaces, said front surface facing said test head during juxtaposition of said test head and said nest, and further wherein said anvil is inserted into said channel from said back surface of said plate.

19. The test apparatus of Claim 17 further comprising a handler onto which said nest is mounted, said anvil held in place in said nest by the juxtaposition of said nest on said handler.